

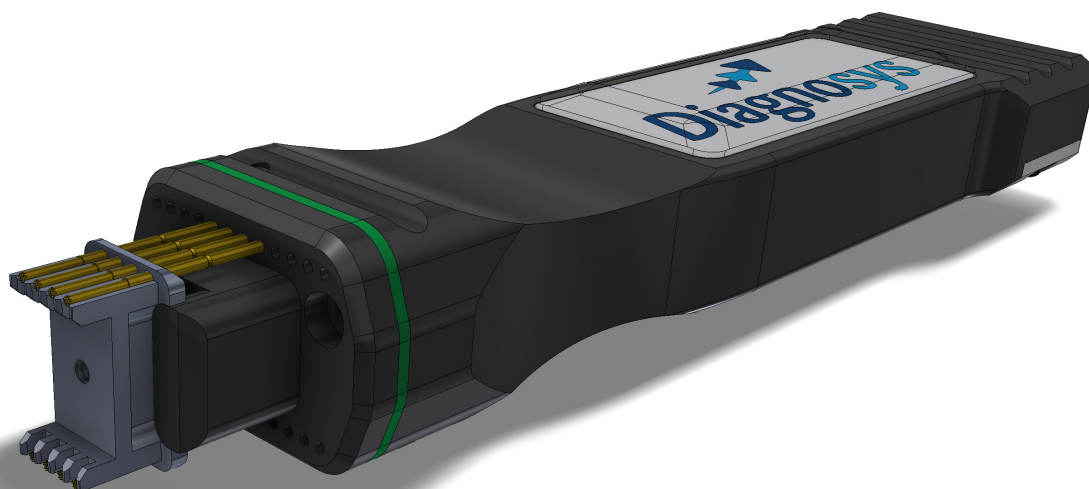
## Introduction

This Test Interface is a hand held test clip which is designed to probe simultaneously the leads of an in-circuit IC. Terminated with a 25 way male "D" type connector, the interface makes temporary electrical contact with the leads of the device, in a two step action:

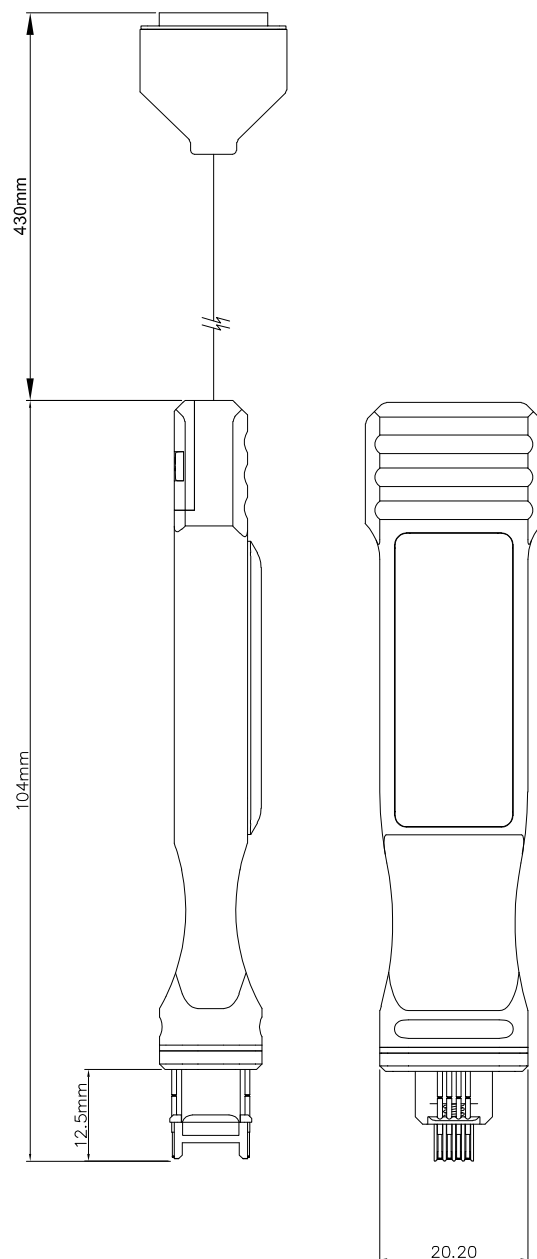
- The interface is positioned over the device to be tested (lining it up with the body of the device and the leads).
- Once it has located on the device, by gently pushing further, the high-performance probes will reach the leads of the device and make electrical contact.

## Features

- achieves the best combination of reliability, repeatability, serviceability and user-friendliness;
- high contact pressure at probe tip (crown type), for repeatable and reliable contact;
- high reliability and long life probes;
- sweeping action gold plated contacts, for reliable contact and low ohmic resistance of interconnections;
- high current rating (for single channel, in ambient air with 70°F [20°C]) : 1.5A
- impact, solvent and temperature resistant plastics, with low friction;
- wide range of operating temperatures (commercial): [0°C to +70°C]
- clear markings on the body, indicating Pin 1 of IC being tested, to prevent probing the wrong way round;
- packaged in a hard wearing, high resistance to damage Polypropylene case with foam insets, the Test Interface can withstand high impact in transit.
- case can be used for safe storage when the Test Interface is not in use, and subsequent transport.



- It will accommodate 8 Pin Wide (0.3") SOIC packages - see drawing below for details
- Maximum number of interconnections (channels): 8
- Current rating, with all contacts loaded (maximum continuous current, non inductive): 0.5A /channel
- Contact resistance (average): 80 mΩ /channel
- Insulation resistance: 5MΩ Min.
- Volume resistivity of plastic parts:  $10^{15}$  Ω-cm @ 50%RH.
- Fatigue life of probes: Min. 1,000,000 cycles at normal working distance
- Working distance (normal stroke): 1.5mm;
- Single probe force at point of contact (normal stroke): 0.16N : at working travel: 0.7N

[illegible]

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Diagnosys Test Systems Limited can provide a full range of test clips to meet individual requirements. Any common device packaging styles can be accommodated, or custom designed clips manufactured, for device pitches of 0.4mm and above.